

CC2400 **Reliability Report**

CONCLUSION

The CC2400 meets the Chipcon product reliability gualification standards based on the procedures and tests documented in the following.

Design phase

Design is made for robustness using extensive corner simulations for:

- Process variations
- Minimum/maximum operating temperature
- Minimum/maximum operating voltage
- Minimum/maximum process limitations

Process

The CC2400 is based on the Chipcon SmartRF[®]-03 platform. It is designed in an industry standard 0.18µm mixed signal CMOS process with 1 poly layer and 4 metal layers.

Package reliability (QFN-48 RoHS compatible)

Moisture Sensitivity Level Temp Cycling Thermal shock Test HAST Autoclave

JEDEC Level 3 -65/150°C, 1000 cycles -65/150°C, 500 cycles 130°C / 85% r.h. 168 hrs 121°C / 15 psi / saturated steam, 168 hrs

ESD and Latch-Up

Latch-up testing according to JEDEC 17. Minimum immunity level: ± 100mA at all pins. VDD abs. max. rating + 20% at all supply pins. ESD test according to Mil. Std. 883E 3015 Human Body Model.

Minimum immunity level RF pin groups: 0.5kV, except:

DI to DGUARD	0.1kV	AVDD_RF1 to DGUARD	0.25kV
RF_IO to AVDD_PRE	0.25kV	TXRX_SWITCH to DGUARD	0.25kV
RF_IO to DVDD_ADC	0.25kV	AVDD_SW to DGUARD	0.25kV
RF_IO to DVDD3.3	0.25kV	AVDD_RF2 to DGUARD	0.25kV
RF_IO to DVDD1.8	0.25kV	AVDD_IF2 to DGUARD	0.25kV
RF_IO to AVDD_CHP	0.25kV	DVDD_ADC to DGND_GUARD	0.25kV
RF_IO to GND	0.1kV	DGUARD to DVDD3.3	0.1kV
RF_IO to DGND_GUARD	0.1kV	DGUARD to DVDD1.8	0.1kV
DIO to DGUARD	0.1kV	DGUARD to AVDD_XOSC	0.25kV
AIO to DGUARD	0.25kV	DGUARD to AVDD_CHP	0.25kV
AO&AI to DGUARD	0.1kV	DGUARD to GND	0.1kV
AO&AI to GND	0.1kV	DGUARD to DGND	0.1kV
AO&AI to DGND_GUARD	0.25kV	DGUARD to DSUB_PADS	0.1kV
VCO_GUARD to DGUARD	0.25kV	DGUARD to DSUB_CORE	0.1kV
AVDD_VCC to DGUARD	0.25kV	DGUARD to GND_PT	0.25kV
AVDD_PRE to DGUARD	0.25kV	RF_IO to RF_IO	0.25kV



Minimum immunity level non-RF pin groups: 1kV, except:						
DI to AVDD VCC	0.5kV	AO&AI to DSUB CORE	0.75kV			
DI to AVDD PRE	0.75kV	AO&AI to GND PT	0.5kV			
DI to AVDD RF2	0.5kV	VCO GUARD to DVDD1.8				
DI to AVDD IF2	0.75kV	VCO GUARD to DSUB CORE				
DI to AVDD ADC	0.75kV					
DI to DVDD_ADC	0.75kV	AVDD VCC to DGND				
DI to AVDD XOSC	0.75kV	AVDD VCC to DSUB PADS				
DI to AVDD CHP	0.25kV	AVDD VCC to DSUB CORE	0.75kV			
DIO to VCO GUARD	0.5kV	AVDD PRE to DVDD3.3	0.75kV			
DIO to AVDD VCC	0.5kV	AVDD PRE to DVDD1.8	0.75kV			
DIO to AVDD_PRE	0.5kV	AVDD_PRE to DSUB_CORE	0.75kV			
DIO to AVDD_RF1	0.75kV	AVDD_RF1 to DVDD1.8	0.5kV			
DIO to AVDD RF2	0.5kV	TXRX SWITCH to DVDD1.8	0.5kV			
DIO to AVDD IF2	0.75kV	TXRX SWITCH to DSUB CORE	0.75kV			
DIO to AVDD_ADC	0.75kV	AVDD_SW to DVDD1.8	0.5kV			
DIO to DVDD_ADC	0.5kV	AVDD_SW to AVDD_CHP	0.75kV			
DIO to AVDD_CHP	0.5kV	AVDD_SW to DSUB_CORE	0.75kV			
DIO to GND_PT	0.75kV	AVDD_RF2 to DVDD1.8	0.5kV			
AIO to DVDD1.8	0.25kV	AVDD_RF2 to DSUB_PADS	0.75kV			
AO&AI to VCO_GUARD	0.25kV	AVDD_RF2 to DSUB_CORE	0.5kV			
AO&AI to AVDD_VCC	0.5kV	AVDD_IF2 to DVDD1.8	0.5kV			
AO&AI to AVDD_PRE	0.25kV	AVDD_ADC to DVDD1.8	0.5kV			
AO&AI to AVDD_RF1	0.25kV	DVDD_ADC to DVDD1.8	0.5kV			
AO&AI to TXRX SWITCH	0.5kV	DVDD3.3 to AVDD CHP	0.75kV			
AO&AI to AVDD_SW	0.25kV	DVDD1.8 to AVDD_XOSC	0.75kV			
AO&AI to AVDD_RF2	0.25kV	DVDD1.8 to AVDD_IF1	0.5kV			
AO&AI to AVDD_IF2	0.25kV	DVDD1.8 to AVDD_CHP	0.5kV			
AO&AI to AVDD_ADC	0.5kV	DVDD1.8 to GND_PT	0.5kV			
AO&AI to DVDD_ADC	0.25kV	AVDD_XOSC to AVDD_IF1	0.75kV			
AO&AI to DVDD3.3	0.75kV	AVDD_XOSC to AVDD_CHP	0.75kV			
AO&AI to DVDD1.8	0.5kV	AVDD_CHP to DGND	0.75kV			
AO&AI to AVDD_XOSC	0.5kV	AVDD_CHP to DSUB_CORE	AVDD_CHP to DSUB_CORE 0.5kV			
AO&AI to AVDD_IF1	0.5kV	AO&AI to AO&AI	0.5kV			
AO&AI to AVDD_CHP	0.5kV					
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Transfer to Production

First Article Inspection (testing at -40/+25/+85°C) Production test limits extraction based on statistical methods. Accelerated lifetime test. Minimum expected lifetime (*): 10 years at 58°C, 1.4 years at 85°C, FIT of approx. 60 (at room temp) with 60% confidence level. (*) based on test of 9 devices at 125°C and 1 at 25°C for 1040hrs, 0 failures. Devices from lot 0447XAB - WAC.

Production test

Final test +25°C Sampling test (-40/+25/+85 °C)

Tape & Reel specification

Package: QFN 48 - RoHS compatible Tape Width: 16,0mm Component Pitch: 12,0mm Hole Pitch: 4,0mm 13inch tape with 4000 pcs.



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Carrier tape and reel is in accordance with EIA specification 481.

Solderability

Recommended soldering profile is according to IPC/JEDEC J-STD-020C July 2004

Summary

The above data show that CC2400 meets the Chipcon product reliability qualification standards and has an acceptable level of reliability.

Revision history

1.0 Initial Version



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